



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Christian Wagner et al. Art Unit : 2161
Serial No. : 09/934,817 Examiner : Etienne Pierre Leroux
Filed : August 21, 2001 Conf. No. : 9363
Title : OPTICAL ARRANGEMENT AND PROJECTION EXPOSURE SYSTEM FOR
MICROLITHOGRAPHY WITH PASSIVE THERMAL COMPENSATION

MAIL STOP RCE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

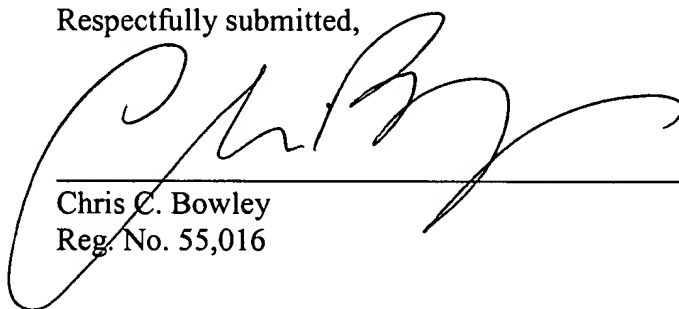
INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

Date: 1/12/2007

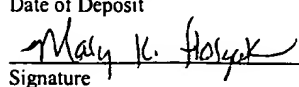

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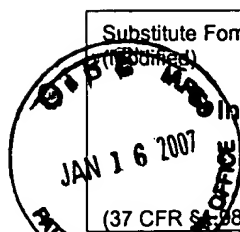
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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

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January 12, 2007
Date of Deposit

Signature

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Typed or Printed Name of Person Signing Certificate

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|--|---|--|---------------------------------------|-------------------------------|
|  | Substitute Form PTO-1449 (37 CFR § 1.98(b)) | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 17979-050001 | Application No. 09/934,817 |
| | Information Disclosure Statement by Applicant (Use several sheets if necessary) | | Applicant Christian Wagner et al. | |
| | | | Filing Date August 21, 2001 | Group Art Unit 2161 |

U.S. Patent Documents

| Examiner Initial | | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
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Foreign Patent Documents or Published Foreign Patent Applications

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation | |
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| | | | | | | | Yes | No |
| | AUU | EP 0678768 | Oct. 25, 1995 | Europe | | | | |

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| Examiner Signature | Date Considered |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |

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| Substitute Form PTO-1449 (Modified) | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 17979-050001 | Application No. 09/934,817 |
| Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b)) | | Applicant Christian Wagner et al. | |
| | | Filing Date August 21, 2001 | Group Art Unit 2161 |

| Foreign Patent Documents or Published Foreign Patent Applications | | | | | | | | |
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| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation | |
| | | | | | | | Yes | No |
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| Other Documents (include Author, Title, Date, and Place of Publication) | | |
|---|-----------|----------|
| Examiner Initial | Desig. ID | Document |
| | AJJJ | |
| | AKKK | |

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| Examiner Signature | Date Considered |
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